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The Effect of Annealing Temperature and Time on the Optical Properties of SnS Thin Films Prepared by Chemical Bath Deposition

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Abstract

A research on the deposition and Characterization of SnS Thin Films by Chemical Bath Deposition Technique using Ammonia (NH₃) as a complexing agent. Thin film of Tin (II) sulphide (SnS) is deposited onto glass substrates using chemical bath deposition (CBD) at room temperature for 3hours and 1hour. The optical properties of the film were measured using Double Beam UV- Spectrophotometer with serial number UV061514, Energy dispersive X-ray florescence (EDXRF) determines the compositions together with Rutherford Back Scattering (RBS) analysis revealed that thin films have percentage compositions of the elements (Sn/S, 50.1/49.9 for 3hours and Sn/S, 50.4/49.6 for 1hour) and their thicknesses are 100nm for 3hours and 150nm for 1hour. It was found that SnS thin film exhibits p-type conduction. Optical band gap values of direct and indirect transitions are estimated to be 1.98eV to 2.01eV and 1.82eV to 1.98eV for the two samples respectively. The other optical properties calculated from transmittance using appropriate equations are absorbance, reflectance, band gap , absorption coefficient, optical conductivity, refractive index and extinction coefficient.

Introduction

Rapid advances in renewable energy technology and implementation will be needed in the next several decades in order to ensure a stable electricity which will lead to smooth transition away from fossil fuels and nuclear energy, which comprised about 93% of the world's energy budget with a negligible contribution from solar energy. And also demand for development of smaller and smaller devices with higher speed and performance which is applicable in the world of technology called Nanotechnology[1]. Among these possible materials is Tin (II) Sulfide (SnS), a non-toxic, abundant, p-type absorber well matched for solar absorption with high absorption coefficient. In recent years, thin films of SnS have attracted much attention for the photovoltaic applications due to the high absorption coefficient and high conductivity[1,2]. Tin (II) sulphide

thin films attracted extensive interest due to their photoconductivity properties for solar energy conversion. SnS thin films can be generated by many methods such as thermal evaporation[3], pulse electron deposition[4], spray pyrolysis[5], SILAR[6], chemical bath deposition[7]. The film in this study is grown by chemical bath deposition (CBD) which creates a thin film on a solid substrate via a reaction in a liquid solution. The CBD method is inexpensive, easy to prepare and its necessary vessels can be found in an ordinary chemistry laboratory. Therefore, this method has many advantages over others used to grow semiconductor thin films. The direct and indirect band gaps of SnS thin film vary depending on the method of preparation and fabrication but some results agree with the literature values between 1.0eV-1.2eV and 1.2eV-1.5eV respectively. SnS thin has been used as an absorption layer in the manufacture of heterojunction solar cell due to its narrow band gap[8,9].

Experiment

In the present work SnS thin films were prepared by chemical bath deposition on microscope glass substrate kept at room temperature with varying other compounds. To make 50ml solution, 0.5M solution of SnCl_2 which is the source of Sn^{+2} was made to react with 3M of 99% Ammonia as complexing agent Subsequently with 1M solution of Thiourea which is the source of S-2. 1M of Sodium hydroxide was added create an alkaline environment for deposition to take place and deionized water added to make-up to 50ml in a glass beaker. Cleaned glass substrates were immersed into the solution and were allowed between 60 to 180 minutes after which the substrates were removed and rinsed in de-ionized water and were allowed to dry in air . Different samples of SnS thin films with A and B chosen as representative samples.

Results and Discursion

In the deposition processes, deposition time, annealing temperatures, pH of solution and annealing time were considered, and changes in the properties of the films were observed. Many samples were deposited under varying conditions. Two samples A and B were chosen as representative samples. They were deposited at room temperature, with pH value of 8.8. Samples A and B were subjected to annealing temperatures of 250oC and 200oC and annealing time of 3hours and 1hour respectively. Thickness is measured by optical method using Rutherford Backscattering (RBS) equipment. The films were subjected to optical measurements using double beam UV- Spectrophotometer with wavelength ranging from 200-1100nm.

Optical Properties

The values of optical transmittance, T were obtained from a Double Beam UV-Spectrophotometer in the range from 200-1100nm. In order to estimate the optical band gap, the equation connecting the photon energy and optical absorption is used:

$$(\alpha h\nu) \propto (h\nu - E_g)^n$$

$$(\alpha h\nu) = f(h\nu - E_g)n$$

where E_g is the energy band gap, α is the absorption coefficient, f is the constant which depends on the film, n is a coefficient having the value 1/2 or 2 depending on the nature of electronic transitions and h is Planck constant. n has the value 1/2 for allowed direct transition, and 2 for allowed indirect transition. Figure 3 shows the optical transmission spectrum of the SnS thin films. The point where the linear part of $(\alpha h\nu)^2$ against $(h\nu)$ graph intersects the $h\nu$ axis gives the forbidden band value for allowed direct transitions; on the other hand, the point where linear part of $(\alpha h\nu)^{1/2}$ against $(h\nu)$ graph intersects the $h\nu$ axis gives us the forbidden band value for allowed indirect transitions. The two graphs of direct and indirect band gap are given in Fig. 4. and Fig. 5 respectively. The direct band gap of the two samples are estimated to be 1.98eV and 2.01eV for the samples annealed for 3hours and 1hour respectively. The indirect band gap of the two samples were estimated to be 1.82eV and 1.98eV for the samples annealed for 3hours and 1hour respectively.

Conclusion

In summary, SnS thin film was successfully deposited onto glass substrates by chemical bath deposition technique at room temperature for 3hours and 1hour. Energy dispersive X-ray florescence (ED-XRF) shows there is a presence of SnS on the slide. According to Rutherford Backscattering (RBS), the thickness of the two samples were measured to be 100nm and 150nm for 3hours and 1hour respectively, also the composition of the thin film on the substrates shows that there is a presence of Sn and S. Optical studies reveal that the film has high transmittance and high optical conductivity which will absorb photons faster. The direct band gaps of the two samples were found to be 1.98eV and 2.01eV for the samples annealed for 3hours and 1hour respectively. The indirect band gaps of the two samples were found to be 1.82eV and 1.98eV for the samples annealed for 3hours and 1hour respectively. Due to the suitable direct band gap value for an absorbing layer for efficient light absorption. Finally, SnS thin films can be used as absorber layer in solar cells.

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